SUPPLEMENTAL MATERIAL

Chemometric Evaluation of Ultraviolet–Visible (UV–Vis) Spectra for Characterization of Silver Nanowire Diameter and Yield

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Figure S1. Scanning Electron Microscope images of four different AgNW samples. (a) and (b) are reactor products. (c) and (d) are reactor products after cross-flow filtration to remove particles.



Figure S2. Absolute wire diameter standard deviation in nm as a function of average wire diameter for data set used in this report.



Figure S3. Distribution of (a) mean wire diameter in nm, (b) diameter standard deviation in nm, and (c) wire yield for the data set used in this report. The horizontal axes are 'count'.





Wire diameter median (nm) = -743.9 + 2.080 * UVVisMax

Table S1. Fit statistics for wire diameter mean as a function of UV-Vis absorption peak position.

L	inear Fit											
W	/ire diameter	mean	(nm) =	: -999	.6168	+ 2.7912	316*UV-Vis					
m	ах											
	Summary	of F										
	RSquare	RSquare					0.547929					
	RSquare Adj	RSquare Adj				0.543664						
	Root Mean S	Root Mean Square Error				624						
	Mean of Res	Mean of Response				377						
	Observation	Observations (or Sum Wgts)				108						
	Analysis o	Analysis of Variance										
	Sum of											
	Source	DF	Squ	Jares	Mea	n Squar	e F Ratio					
	Model	1	852	5.850		8525.8	5 128.4764					
	Error	106	703	4.289		66.3	6 Prob > F					
	C. Total	107	15560.140				<.0001*					
Parameter Estimates												
	Term	Est	Estimate		Error	t Ratio	Prob> t					
	Intercept	-999	9.6168	93.2	4939	-10.72	<.0001*					
	UV-Vis max	2.79	12316	0.24	6255	11.33	<.0001*					

Table S2. Fit statistics for wire diameter median as a function of UV-Vis absorption peak position.

L	inear Fit							
m	edian diame	ter (nn	n) = -7	43.86	26 + 2	2.079802	2*1	JV-Vis max
	Summary	it						
	RSquare		0.558287					
	RSquare Ad		0.55412					
	Root Mean		5.94406					
	Mean of Re		43.66994					
	Observation	gts)		108				
	Analysis	e						
	Sum of							
	Source	DF	Squ	Jares	Mea	an Squa	re	F Ratio
	Model	1	4733	5832		4733.5	58	133.9750
	Error	106	3745	1760		35.	33	Prob > F
	C. Total	107	8478	7592				<.0001*
	Parameter Estimates							
	Term	Est	imate	Std	Error	t Ratio	F	Prob> t
	Intercept	-743	-743.8626 6		4121	-10.93		<.0001*
	UV-Vis max	2.0798022		0.17	9684	11.57		<.0001*

Table S3. Fit statistics for wire yield as a function of normalized UV-Vis absorbance at 500 nm.

L	inear Fi	t									
w	ire/(Part+	Wire) are	a =	1.02150	29	- 0.7134	461*5	500 nm	1		
	Summa	Summary of Fit									
	RSquare					0.598654					
	RSquare Adj					0.594868					
	Root Mean Square Error Mean of Response Observations (or Sum Wgts)					0.096202					
						91429					
						108					
	Analysis of Variance										
	Sum of										
	Source	Source DF Squa				/lean Sq	FR	atio			
	Model	odel 1 1.4		4632978		1.4633		158.1	113		
	Error	106	0.9	9810151		0.0	0925	Prob	> F		
	C. Total	107	2.4	4443129				<.00)01*		
Parameter Estimates											
	Term Estimate			Std Error t Rati			o Prob> t				
	Intercept	1.02150	29	0.0205	06	49.82	2 <.	0001*			
	500 nm	-0.7134	46	0.0567	39	-12.57	/ <.	0001*			



Figure S5. Wire diameter median as a function of Principal Component scores.



Figure S6. Principal Component Loadings.



Figure S7. Principal Component Scores.